

# INFORMATION DISCLOSURE STATEMENT

PTO-1449 (PAGE 1 OF 1)

SERIAL NUMBER 10/759,098

DOCKET NO. P57021

APPLICANT

Hyeong-Rae SEON, et al.

FILING DATE 20 January 2004

GROUP

2879

## U.S. PATENT DOCUMENTS

EXAMINER	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
<i>AW</i>	1020020011617	2/9/02	KOREA	—	—	Abstract	
<i>AW</i>	2000-086216	3/28/02	JAPAN	—	—	Abstract	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>AW</i>	Notice to Submit Response, 4/28/2005 issued by the Korean Intellectual Property Office in Applicant's co-pending Korean priority application assigned Serial No. 10-2003-0044534.

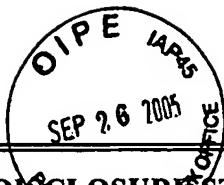
EXAMINER:

*John W. Wilkes*

DATE CONSIDERED:

10/29/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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~~to be assigned~~

**U.S. PATENT DOCUMENTS**

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASSES	FILING DATE
JW	6,580,211 B1	06/03	Yang et al.	_____	_____	
JW	6,377,002 B1	04/02	Ge et al.	_____	_____	
JW	6,765,346	10/03	Lee et al.	_____	_____	
JW	2003042841 A	07/02	Ku et al.	_____	_____	
JW	2002024296 A1	02/02	Uemura et al.	_____	_____	

**FOREIGN PATENT DOCUMENTS**

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASSES	YES	NO
JW	1020020011617	02/02	Korea	_____	_____	Abstract	
JW	1020010081496 A	08/01	Korea	_____	_____	Abstract	
JW	1020030077852	10/03	Korea	_____	_____	Abstract	
JW	1146541 A2	10/01	Europe	_____	_____		
JW	0854493 A1	07/98	Europe	_____	_____		

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)**

	<i>European Office Action</i> issued by the European Patent Office in applicant's corresponding European Patent Application No. EP 04250272, issued on 22 August 2005.
JW	Database WPI Section EI, Week 200265, XP002338968, published on 9 February 2002(same as KR 1020020011617 to Choi et al.)
JW	Database WPI Section EI, Week 200240, XP002338969, published on 29 August 2001(same as KR 1020010081496 A to Choi et al.)
JW	Journal of Vacuum Science and Technology: Part B, vol. 18, no. 2, entitled <i>INTEGRATION OF HIGH VOLTAGE FIELD EMISSION DISPLAY FOLLOWED BY MACRO- AND NANOSTRUCTURAL ANALYSIS ON MICROTIP</i> , XP001189083, published on March 2000
JW	Database WPI Section EI, Week 200410, XP002338970, published on 20 July 2004

EXAMINER:

*Joseph Williams*

DATE CONSIDERED:

*11/29/05*

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